# Sequential Testing and Quickest Detection for a Multi-dimensional Wiener Process

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January 24, 2020

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## Another Look at the 1D case

■ let *Y* be a continuous-time Markov chain with state space {0,1} and transition matrix

$$Q = \begin{pmatrix} -\lambda & \lambda \\ 0 & 0 \end{pmatrix}$$

where  $\lambda \ge 0$  is a known constant.

• 
$$\mathbb{P}(Y_0 = 1) = \pi$$
 and  $\mathbb{P}(Y_0 = 0) = 1 - \pi$  for  $\pi \in [0, 1]$ .

let X be

$$X_t = \int_0^t Y_s \, ds + W_t,$$

where W is a 1D standard BM independent of Y.

-Can then reformulate the classical problems of sequential testing and Bayesian quickest detection.

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## Another Look at the 1D case

## **Sequential Testing**

## **Quickest Detection**

- $1 \quad \lambda = 0, \ Y_t = Y_0,$
- 2 Want to determine  $Y_0$ .
- 3 i.e. Consider

 $\inf_{\tau,d} \left\{ \mathbb{P}(d \neq Y_0) + c\mathbb{E}[\tau] \right\},\$ 

### 1 $\lambda > 0$

- 2 Want to determine the jump time of  $Y_t$ .
- 3 i.e. Consider

$$\inf_{\tau} \left\{ \mathbb{P}(Y_{\tau} = 0) + c \mathbb{E}\left[ \int_{0}^{\tau} Y_{t} dt \right] \right\}$$

where  $\tau$ 's are  $\mathscr{F}^X$ -stopping times and  $d \in \{0,1\}, \mathscr{F}^X_{\tau}$ -measurable.

## **Reduction to Optimal Stopping**

- Define the conditional probability process  $\Pi_t := \mathbb{E}[Y_t | \mathscr{F}_t]$ ,
- Both problems can be written as:

$$\inf_{\tau} \mathbb{E}\left[g(\Pi_{\tau}) + \int_{0}^{\tau} h(\Pi_{s}) \, ds\right]$$

#### ■ g and h are certain penalty functions:

- - Testing:  $g(\pi) = \pi \wedge (1 \pi)$  and  $h(\pi) = c$ ,
- - Detection:  $g(\pi) = (1 \pi)$  and  $h(\pi) = c\pi$ .

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## The Higher-dimensional Version

- Observe: *n*-dimensional BM  $X_t$  with drift
- Drift of  $X_i$  is modelded by  $Y^i$  (mutually independent) with state space  $\{0,1\}$  and transition matrix

$$Q^i = \begin{pmatrix} -\lambda^i & \lambda^i \\ 0 & 0 \end{pmatrix},$$

where  $\lambda^{i} \ge 0$  **P** $(Y_{0} = 1) = \pi_{i} \in [0, 1]$  **(** $X_{t})_{t \ge 0} = (X_{t}^{1}, X_{t}^{2}, ..., X_{t}^{n})_{t \ge 0}$  is then given by  $dX_{t}^{i} = Y_{t}^{i} dt + dW_{t}^{i}$ 

- $W^i, \ldots, W^n$  are independent BMs, Y and W are independent.
- Introduce  $\Pi = (\Pi^1, \dots \Pi^n)$ :

$$\Pi_t^i := \mathbb{E}[Y_t^i | \mathscr{F}_t]$$

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The Higher-dimensional Version

We study a family of problems which can be written as:

$$\inf_{\tau} \mathbb{E}\left[g(\Pi_{\tau}) + \int_0^{\tau} h(\Pi_t) \, dt\right]$$

for  $g, h : [0, 1]^n \to [0, \infty)$  of the process  $\Pi$ .

Assumptions



- 3 g, h Lipschitz continuous
- 4 g,h concave in each direction separately.

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### Some Formulations-Sequential Testing

Assume  $\lambda_i = 0$  and h = c for some c > 0.

SQ1: Penalizing each faulty decision equally

$$\inf_{\tau,d} \left\{ \sum_{i=1}^{n} \mathbb{P}(d_i \neq Y_0^i) + c\mathbb{E}[\tau] \right\}$$
$$g(\pi) = \sum_{i=1}^{n} \pi_i \wedge (1 - \pi_i)$$

SQ2: Penalized for at least one faulty decision

$$\inf_{\tau,d} \left\{ \mathbb{P}(\{d_i \neq Y_0^i \text{ for some } i\}) + c\mathbb{E}[\tau] \right\}, \\ g(\pi) = 1 - \prod_{i=1}^n (1 - \pi_i \wedge (1 - \pi_i))$$

SQ3: Determine one drift *d* and point out its coordinates  $\tilde{d}$  $\inf_{\tau,d,\tilde{d}} \left\{ \mathbb{P}(d \neq Y_0^{\tilde{d}}) + c\mathbb{E}[\tau] \right\}, \ g(\pi) = \wedge_{i=1}^n \pi_i \wedge (1 - \pi_i)$ 

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#### Some Formulations-Sequential Testing

**SQ4**: With cost reduction, n = 2

$$\inf_{\substack{\tau_1, \tau_2, d_1, d_2}} \{ \mathbb{P}(d_1 \neq Y_0^1) + \mathbb{P}(d_2 \neq Y_0^2) + \\ c \mathbb{E}[\tau_1 \wedge \tau_2 + (1 - \lambda)(\tau_1 \vee \tau_2 - \tau_1 \wedge \tau_2)] \}$$

Can be reduced to one stopping rule
g(π) = ∧<sup>2</sup><sub>i=1</sub>(π<sub>i</sub> ∧ (1 − π<sub>i</sub>) + V<sub>c(1−λ)</sub>π<sub>3−i</sub>) where V<sub>c(1−λ</sub> is the value function of the 1D testing problem with cost c(1 − λ).
when λ = 0 same as SQ1, when λ = 1 same as SQ3.

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### **Some Formulations-Quickest Detection**

QD1: The first changing point

$$\inf_{\tau} \left\{ \mathbb{P}\left( \max_{1 \le i \le n} Y_{\tau}^{i} = 0 \right) + c \mathbb{E}\left[ \int_{0}^{\tau} \max_{1 \le i \le n} Y_{t}^{i} dt \right] \right\}$$
$$g(\pi) = \prod_{i=1}^{n} (1 - \pi_{i}), \quad h(\pi) = c(1 - \prod_{i=1}^{n} (1 - \pi_{i}))$$

QD2: The *last* changing point

$$\inf_{\tau} \left\{ \mathbb{P}\left(\min_{1 \le i \le n} Y_{\tau}^{i} = 0\right) + c \mathbb{E}\left[\int_{0}^{\tau} \min_{1 \le i \le n} Y_{t}^{i} dt\right] \right\}$$
$$g(\pi) = 1 - \prod_{i=1}^{n} \pi_{i}, \quad h(\pi) = c \prod_{i=1}^{n} \pi_{i}$$

QD3: Determine one change point and point out its coordinates d

$$\inf_{\tau,\tilde{\sigma}} \left\{ \mathbb{P}(Y_{\tau}^{\tilde{\sigma}} = 0) + c\mathbb{E}\left[\int_{0}^{\tau} \sum_{i=1}^{n} Y_{t}^{i} dt\right] \right\},\$$
$$g(\pi) = \wedge_{i=1}^{n} (1 - \pi_{i}), \quad h(\pi) = c \sum_{i=1}^{n} \pi_{i}$$

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## **Unilateral Concavity**

The function  $\pi_i \mapsto V(\pi)$  is concave in each variable separately (i.e.  $\pi_i \mapsto V(\pi)$  is concave for each i = 1, ..., n).

### Some Other Results

- 1 The cost function V is Lipschitz continuous.
- **2** The set  $\{\mathscr{L}g + h < 0\}$  is contained in  $\mathscr{C}$ .
- 3 The kinks in the g function are contained in  $\mathscr{C}$ .

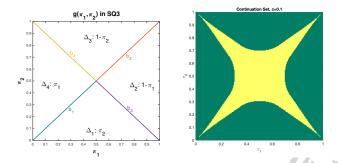
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### SQ3: Testing with Pointing the Direction

$$1 \quad g(\pi) = \wedge_{i=1}^n \pi_i \wedge (1 - \pi_i)$$

- 2 The diagonals are contained in  $\mathscr{C}$
- 3 The square  $[A_*, 1 A_*] \times [A_*, 1 A_*]$  is contained in the continuation region.



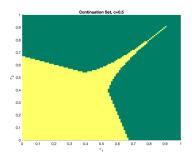
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### **QD3: Detection with Pointing out the Direction**

$$1 \quad g(\pi) = 1 - \pi_1 \vee \pi_2$$

- **2** The diagonal  $\{\pi_1 = \pi_2\}$  is contained in  $\mathscr{C}$ ,
- 3 One can find a crude upper bound for  $\mathscr{C}$ :  $\pi_2 < \frac{\lambda}{c} (\frac{\lambda}{c} + 1)\pi_1$ ,
- 4 By connecting with the 1D problem, one can show that the stopping region intersects  $\pi_1$  axis at some  $\exists C^* \in [\frac{\lambda}{\lambda+c}, 1)$ .



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Summary						

- Reformulate the 1D testing and detection problems as one,
- Extend it into a family of *multi-dimensional* stopping problems with *one* stopping rule and *independence* in the driving Brownian motions,
- Prove unilateral concavity and some other general properties,
- **Give some formulations** in this family possibly with applications.

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